



MAPLE/SCALE 2011

Joint workshop of the
 3rd International Workshop on Model-driven Approaches in Software Product Line Engineering and
 3rd Workshop on Scalable Modeling Techniques for Software Product Lines
 held in conjunction with SPLC 2011, 22-26 August 2011, Munich, Germany

1. MOTIVATION

Many of the benefits expected from software product lines (SPL) are based on the assumption that the additional investment required for domain engineering, pays off during application engineering when products are derived from the product line. However, to fully exploit this we need to optimize application engineering processes and handle the reusable artefacts of an SPL in a systematic and efficient manner.

In this context, the joint MAPLE/SCALE workshop will focus on two closely related aspects: We will explore how **model-driven** approaches can help to achieve systematic and efficient derivation of products and we will address **scalability** challenges that arise from the application of product line techniques to product lines of realistic size and complexity.

The workshop particularly aims at bringing together researchers and practitioners to discuss practical problems and potential solutions regarding model-driven approaches and/or scalability challenges.

2. TOPICS

We particularly encourage research papers based on **industrial experience** and empirical studies. We are interested in all topics related to model-driven techniques and/or scalability in product line engineering. This includes, but is not limited to:

- Modelling of software product lines
 - Variability modelling
 - Configuration vs. construction of products (e.g. with DSLs)
 - Scalability of product line models
- Product derivation/configuration
 - Automated and interactive techniques
 - Scalability of derivation/configuration
- Assembly/generation of SPL artefacts

- Handling large and complex SPLs
 - Managing complexity, scalability and inconsistencies
- Visualisation and interactive techniques for large and complex PL models
 - To support modelling of SPLs
 - To support product derivation
- Feature-oriented approaches for modelling and implementation
 - Feature dependencies and feature interaction
- Evolution and Change
 - Model/Meta-model (co-)evolution
 - Model maintenance (merging, conflict resolution)
- Variability-aware and scalable techniques for validation and verification
- Integration of heterogeneous modelling languages and techniques
- Runtime-variability, dynamic SPLs, variability in adaptive systems
- Collaborative and distributed scenarios, software ecosystems

We particularly encourage papers which

- report on industrial experience and case studies and/or
- identify and structure open challenges and research questions

3. SUBMISSIONS

We are seeking for research papers and experience reports (4–8 pages) in [ACM SIG Alternative Proceedings Style](#). Submissions will be selected based on the relevance to the workshop topics (submissions must address model-driven approaches and/or scalability in PLE) and the suitability to trigger discussions. Papers should be submitted as PDF files via EasyChair at <https://www.easychair.org/conferences/?conf=maplescale2011>

4. IMPORTANT DATES (EXTENDED!)

Deadline for submissions: **28th May 2011**
 Notification of acceptance: **15th June 2011**
 Final papers due: **27th June 2011**

5. ORGANIZATION

PROGRAM COMMITTEE

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 ... and the workshop organizers

WORKSHOP ORGANIZATION

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WEBSITE

For additional information see
<http://www.lero.ie/maplescale2011>